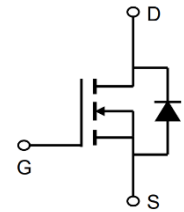


30V N-Channel Enhancement Mode MOSFET

Description

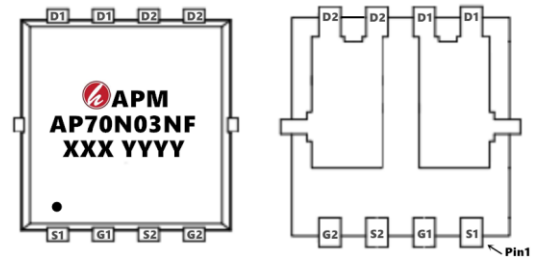
The AP70N03NF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



General Features

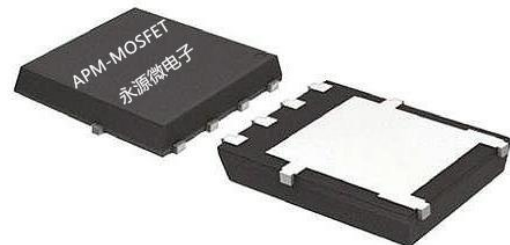
$V_{DS} = 30V$ $I_D = 70A$

$R_{DS(ON)} < 5.5m\Omega @ V_{GS}=10V$



Application

Battery protection
 Load switch
 Uninterruptible power supply



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|------------|--------------------|----------|
| AP70N03NF | PDFN5*6-8L | AP70N03NF XXX YYYY | 5000 |

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Rating | Units |
|-------------------------------|--|------------|--------------------|
| V_{DS} | Drain-Source Voltage | 30 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | V |
| $I_D @ T_C=25^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 70 | A |
| $I_D @ T_C=100^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 51 | A |
| $I_D @ T_A=25^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 15 | A |
| $I_D @ T_A=70^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 12 | A |
| I_{DM} | Pulsed Drain Current ² | 160 | A |
| EAS | Single Pulse Avalanche Energy ³ | 115.2 | mJ |
| I_{AS} | Avalanche Current | 48 | A |
| $P_D @ T_C=25^\circ\text{C}$ | Total Power Dissipation ⁴ | 59 | W |
| $P_D @ T_A=25^\circ\text{C}$ | Total Power Dissipation ⁴ | 2 | W |
| T_{STG} | Storage Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| T_J | Operating Junction Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient ¹ | 62 | $^\circ\text{C/W}$ |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ¹ | 2.1 | $^\circ\text{C/W}$ |

30V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25°C, unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|------------------------|--|---|------|-------|------|-------|
| BVDSS | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =250uA | 30 | --- | --- | V |
| ΔBVDSS/ΔT _J | BVDSS Temperature Coefficient | Reference to 25°C, I _D =1mA | --- | 0.028 | --- | V/°C |
| RDS(ON) | Static Drain-Source On-Resistance | V _{GS} =10V, I _D =30A | --- | 3.5 | 5.5 | mΩ |
| | | V _{GS} =4.5V, I _D =15A | --- | 6.5 | 8.5 | |
| VGS(th) | Gate Threshold Voltage | V _{GS} =V _{DS} , I _D =250uA | 1.0 | 1.6 | 2.5 | V |
| ΔVGS(th) | VGS(th) Temperature Coefficient | | --- | -6.16 | --- | mV/°C |
| IDSS | Drain-Source Leakage Current | V _{DS} =24V, V _{GS} =0V, T _J =25°C | --- | --- | 1 | uA |
| | | V _{DS} =24V, V _{GS} =0V, T _J =55°C | --- | --- | 5 | |
| IGSS | Gate-Source Leakage Current | V _{GS} =±20V, V _{DS} =0V | --- | --- | ±100 | nA |
| gfs | Forward Transconductance | V _{DS} =5V, I _D =30A | --- | 22 | --- | S |
| R _g | Gate Resistance | V _{DS} =0V, V _{GS} =0V, f=1MHz | --- | 1.7 | 3.4 | Ω |
| Q _g | Total Gate Charge (4.5V) | V _{DS} =15V, V _{GS} =4.5V, I _D =15A | --- | 20 | --- | nC |
| Q _{gs} | Gate-Source Charge | | --- | 7.6 | --- | |
| Q _{gd} | Gate-Drain Charge | | --- | 7.2 | --- | |
| Td(on) | Turn-On Delay Time | V _{DD} =15V, V _{GS} =10V, R _G =3.3Ω I _D =15A | --- | 7.8 | --- | ns |
| T _r | Rise Time | | --- | 15 | --- | |
| Td(off) | Turn-Off Delay Time | | --- | 37.3 | --- | |
| T _f | Fall Time | | --- | 10.6 | --- | |
| C _{iss} | Input Capacitance | V _{DS} =15V, V _{GS} =0V, f=1MHz | --- | 2295 | --- | pF |
| C _{oss} | Output Capacitance | | --- | 267 | --- | |
| C _{rss} | Reverse Transfer Capacitance | | --- | 210 | --- | |
| I _S | Continuous Source Current ^{1,5} | V _G =V _D =0V, Force Current | --- | --- | 80 | A |
| I _{SM} | Pulsed Source Current ^{2,5} | | --- | --- | 160 | A |
| VSD | Diode Forward Voltage ² | V _{GS} =0V, I _S =1A, T _J =25°C | --- | --- | 1 | V |
| t _{rr} | Reverse Recovery Time | I _F =30A, di/dt=100A/μs, T _J =25°C | --- | 14 | --- | nS |
| Q _{rr} | Reverse Recovery Charge | | --- | 5 | --- | nC |

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
2. The data tested by pulsed, pulse width. The EAS data shows Max. rating.
3. The test cond ≅ 300us, duty cycle ition is V_{DD=25} ≅ V, V 2%_{GS} = 10V, L=0.1mH, I_{AS}=53.8A
4. The power dissipation is limited by 175°C junction temperature
5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.

30V N-Channel Enhancement Mode MOSFET

Typical Characteristics

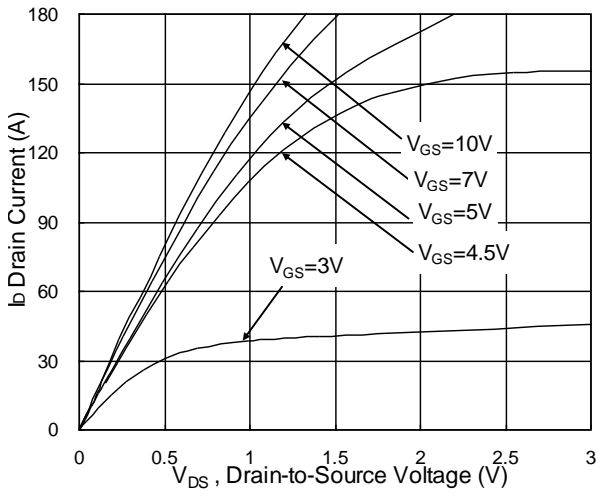


Fig.1 Typical Output Characteristics

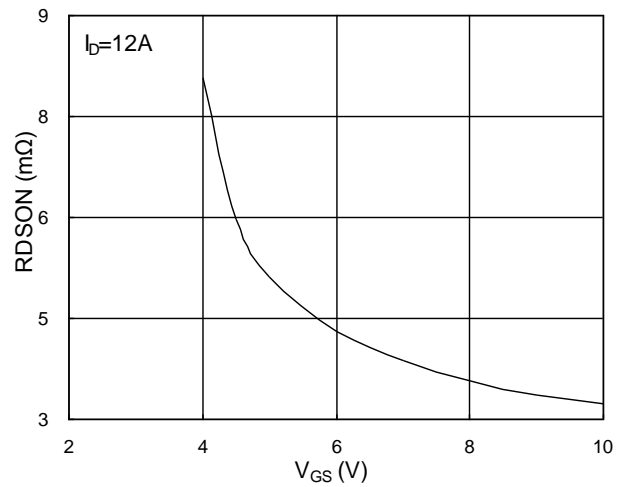


Fig.2 On-Resistance vs. G-S Voltage

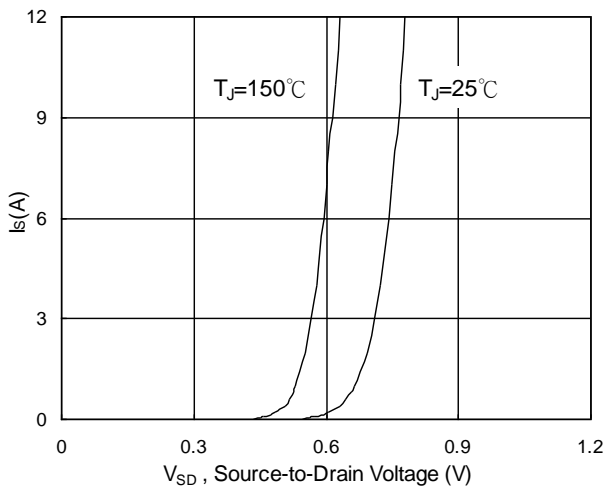


Fig.3 Forward Characteristics of Reverse

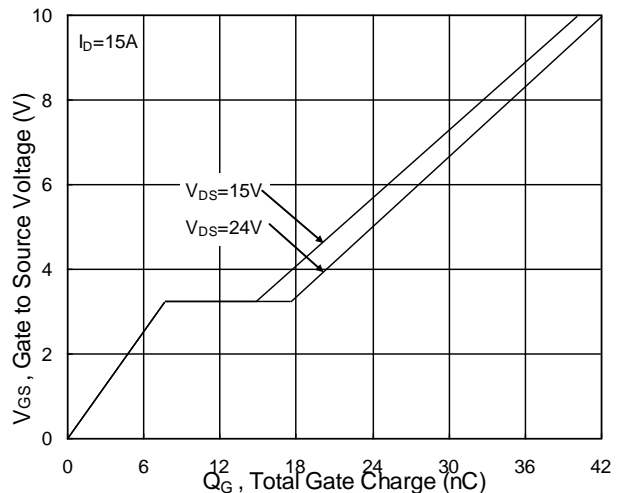


Fig.4 Gate-Charge Characteristics

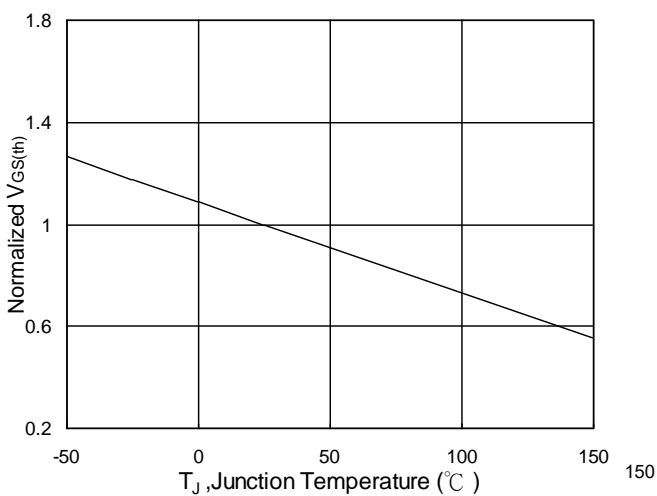


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

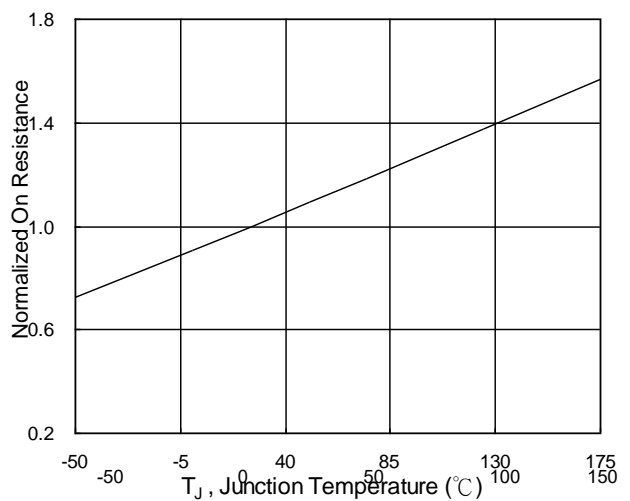


Fig.6 Normalized $R_{DS(on)}$ vs. T_J



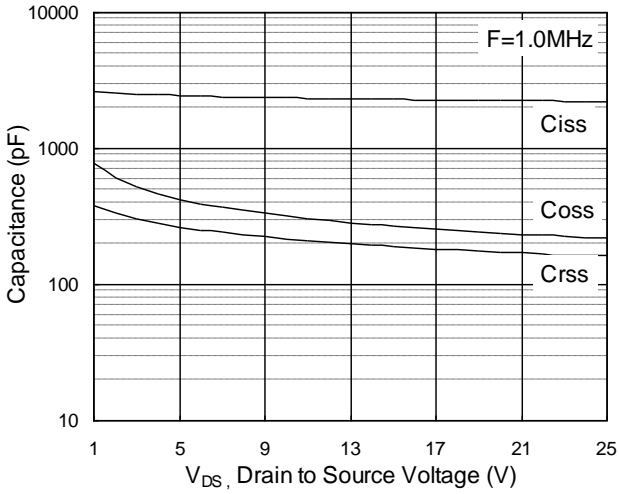


Fig.7 Capacitance

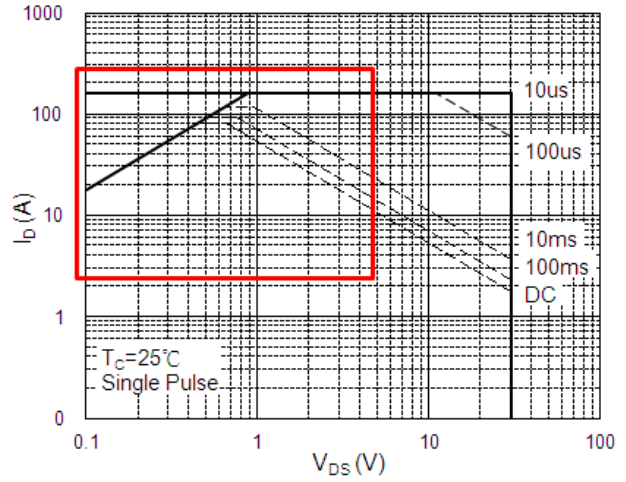


Fig.8 Safe Operating Area

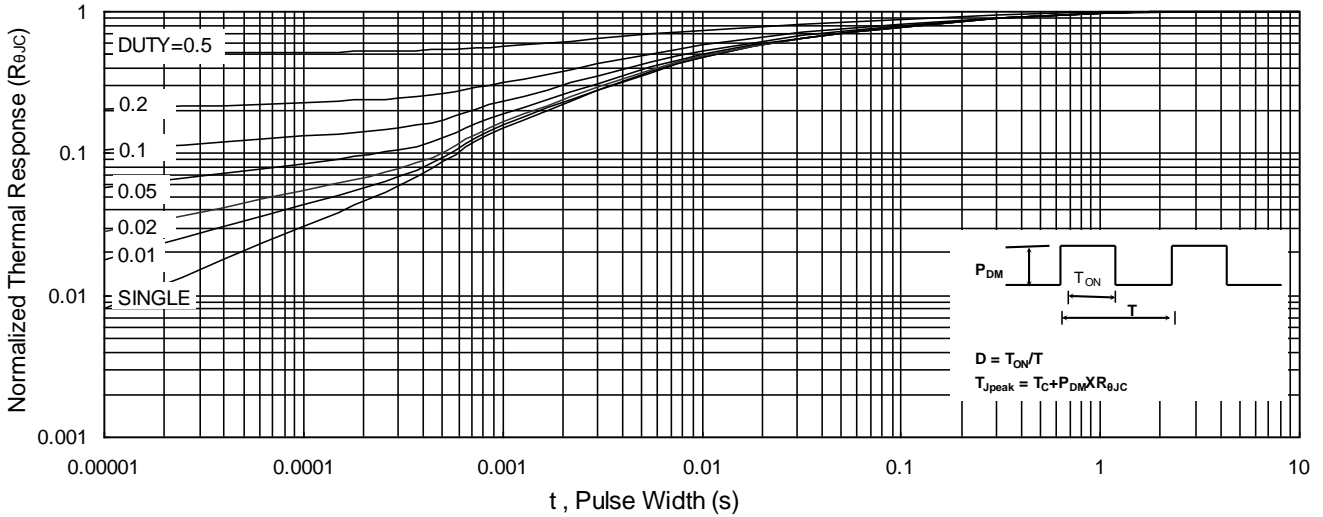


Fig.9 Normalized Maximum Transient Thermal Impedance

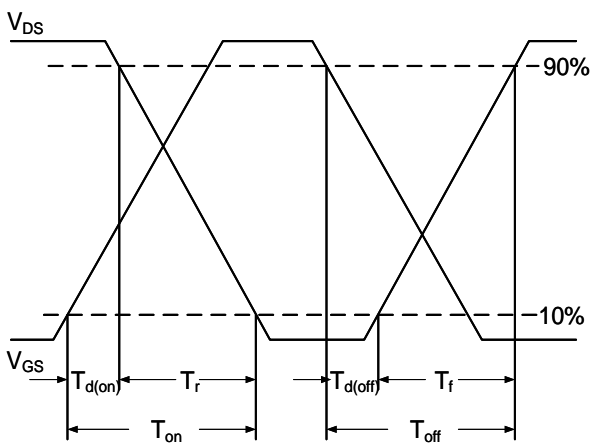


Fig.10 Switching Time Waveform

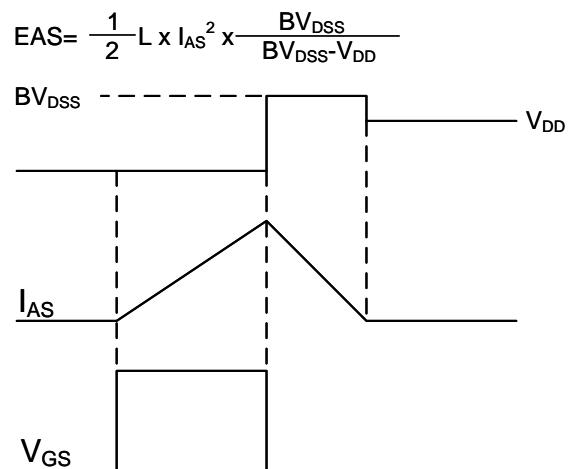
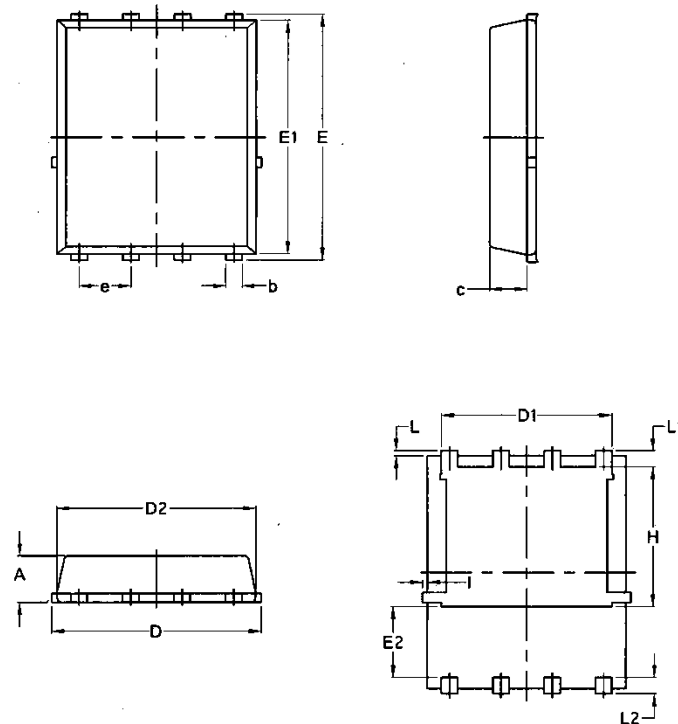


Fig.11 Unclamped Inductive Switching Waveform

Package Mechanical Data-DFN5*6-8L-JQ Single



| Symbol | Common | | | |
|--------|----------|--------|----------|--------|
| | mm | | Inch | |
| | Mim | Max | Min | Max |
| A | 1.03 | 1.17 | 0.0406 | 0.0461 |
| b | 0.34 | 0.48 | 0.0134 | 0.0189 |
| c | 0.824 | 0.0970 | 0.0324 | 0.082 |
| D | 4.80 | 5.40 | 0.1890 | 0.2126 |
| D1 | 4.11 | 4.31 | 0.1618 | 0.1697 |
| D2 | 4.80 | 5.00 | 0.1890 | 0.1969 |
| E | 5.95 | 6.15 | 0.2343 | 0.2421 |
| E1 | 5.65 | 5.85 | 0.2224 | 0.2303 |
| E2 | 1.60 | / | 0.0630 | / |
| e | 1.27 BSC | | 0.05 BSC | |
| L | 0.05 | 0.25 | 0.0020 | 0.0098 |
| L1 | 0.38 | 0.50 | 0.0150 | 0.0197 |
| L2 | 0.38 | 0.50 | 0.0150 | 0.0197 |
| H | 3.30 | 3.50 | 0.1299 | 0.1378 |
| I | / | 0.18 | / | 0.0070 |

30V N-Channel Enhancement Mode MOSFET**Attention**

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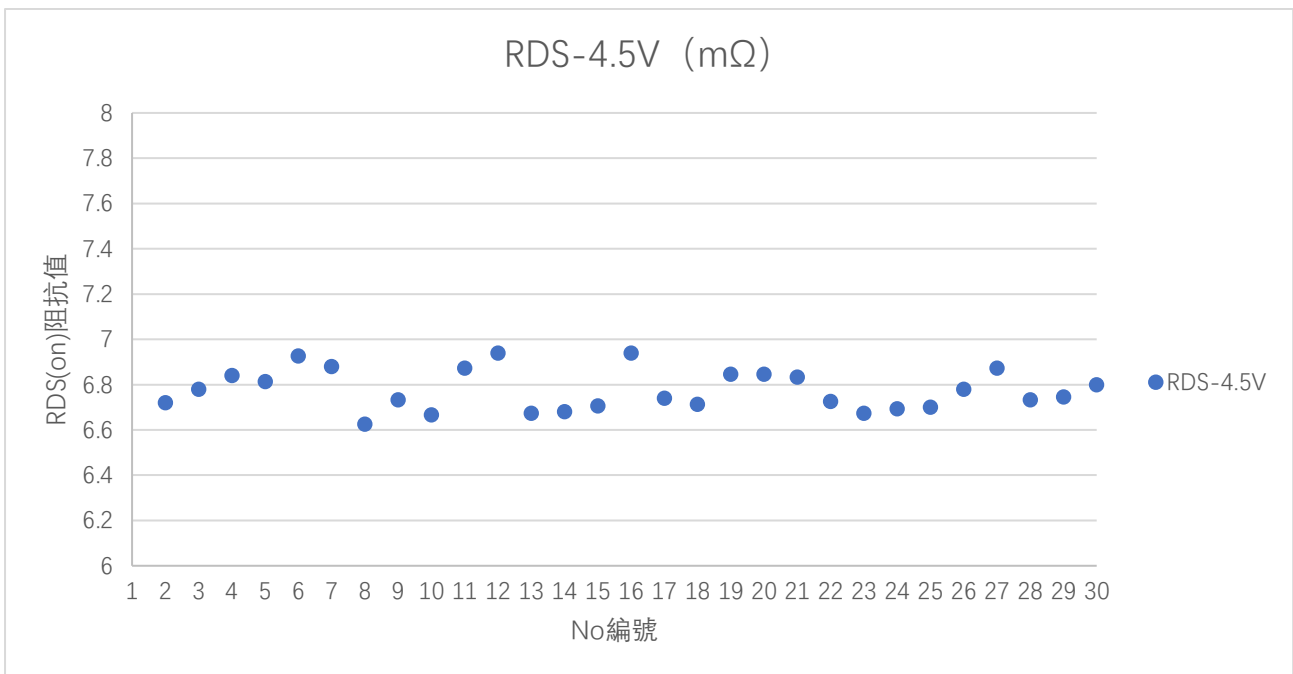
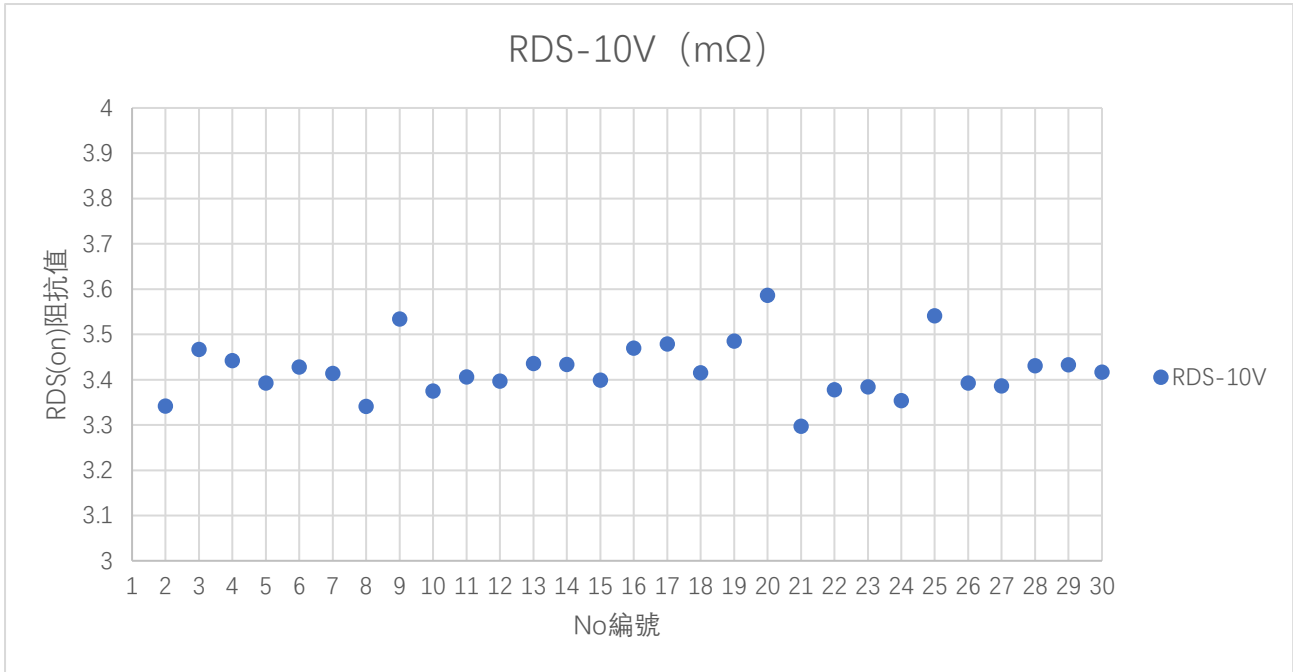
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30V N-Channel Enhancement Mode MOSFET

